arXiv:cond-mat/0512657v1 [cond-mat.stat-mech] 26 Dec 2005

Correlation functions and queuing phenomena in growth processes with drift

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We suggest a novel stochastic discrete growth model which describes the drifted Edward-Wilkinson (EW) equation $\partial h/\partial t = \nu\partial_x^2 h - v\partial_x h + \eta(x,t)$. From the stochastic model, the anomalous behavior of the drifted EW equation with a defect is analyzed. To physically understand the anomalous behavior the height-height correlation functions $C(r) = \langle |h(x_0+r) - h(x_0)| \rangle$ and $G(r) = \langle |h(x_0+r) - h(x_0)|^2 \rangle$ are also investigated, where the defect is located at x_0. The height-height correlation functions follow the power law $C(r) \sim r^{\alpha'}$ and $G(r) \sim r^{\alpha''}$ with $\alpha' = \alpha'' = 1/4$ around a perfect defect at which no growth process is allowed. $\alpha' = \alpha'' = 1/4$ is the same as the anomalous roughness exponent $\alpha = 1/4$. For the weak defect at which the growth process is partially allowed, the normal EW behavior is recovered. We also suggest a new type queuing process based on the asymmetry $C(r) \neq C(-r)$ of the correlation function around the perfect defect.

PACS numbers: 68.35.J, 05.10.G, 11.10.J

I. INTRODUCTION

Occasionally some of the research results on older topics give excellent insights to the subsequent researches. One of the such works is the recent work on the drifted Edward-Wilkinson (EW) equation

$$\frac{\partial h(x,t)}{\partial t} = \nu\partial_x^2 h(x,t) - v\partial_x h(x,t) + \eta(x,t) \ , \quad (1)$$

with a fixed boundary condition (FBC) $h(x_0 = 0, t) = h(x_0 = L, t) = 0$ [1]. If the diffusion term $\nu\partial_x^2 h(x,t)$ is ignored in Eq. (1), one can obtain roughness exponent $\alpha = 0$, growth exponent $\beta = 0$ and dynamic exponent $z = 1$ by a scaling argument and some other methods (1) [1, 2, 3, 4]. But for periodic boundary condition (PBC), the drift term $-v\partial_x h(x,t)$ is irrelevant, and thus Eq. (1) becomes physically equivalent to the normal EW equation [5]

$$\frac{\partial h(x,t)}{\partial t} = \nu\partial_x^2 h(x,t) + \eta(x,t) \ , \quad (2)$$

with $\alpha = 1/2, \beta = 1/4$, and $z = 2$. In contrast, if FBC instead PBC is imposed, the roughness of surface described by Eq. (1) is exactly proved to show an anomalous behavior with the exponents [1],

$$\alpha = 1/4, \quad \beta = 1/4, \quad z = 1 \ . \quad (3)$$

The exact solution for Eq. (1) [1] gives us an excellent insight to understand the role of the drift term and the boundary condition as a relevant extension of the normal EW equation.

The drift term and the diffusion term are crucial for anomalous exponents under FBC [1]. Without the drift term, the maximum time which the roughness is fully developed for the system is order of L^2/ν. If the system is affected by the drift, the time scale that any noise-generated local structure starts from one boundary to the other boundary is $t_\times = L/v$. The fluctuation of the surface width is saturated after this time scale. Therefore $W^2 \sim t_\times^{1/2} \sim L^{1/2}$ and thus one can get the anomalous exponents (3). In Ref. [1], local width is numerically studied to test the validity of this physical mechanism. The local width is increased as $W_l^2(x_l) \propto t_l{}^{1/2} \sim (x_l/v)^{1/2}$, with x_l being the position where the width is measured. But the definition of the local width is not physically clear and there is a sort of difficulty to measure $W_l^2(x_l)$ for the small system.

For last two decades, the stochastic discrete growth models whose dynamical scaling behavior is identical to those of a given continuum growth equation have been used to investigate the dynamical scaling behavior for the corresponding surface roughness [5, 6, 7, 8, 9]. The stochastic discrete growth model is a powerful tool which simplifies the complicate growth behavior and provides an essential link between theory and experiments. For example, the surface growth which is described by normal EW equation has been studied through the Family model [10]. But no simple growth model which exactly corresponds to the drifted EW equation with FBC has been suggested yet. Other existing models cannot explain the anomalous behavior of the surface fluctuation which comes from the drift term and FBC in Eq. (1). First motivation of this paper is thus to make a simple stochastic discrete model which satisfies Eq. (1) with FBC using a stochastic analysis method [11].

Second motivation of this paper is in the explanation of the physical mechanism which causes the anomalous behavior (3) by using a height-height correlation function. The height-height correlation function can be easily treated through our handy stochastic discrete model. As mentioned above, the local width [1] is somewhat unmature physical quantity and has not been widely used for the analysis of surface roughness [6]. In contrast, height-height correlation function has been extensively used to show the exact dynamic scaling in the surface growth physics [6]. The height-height correlation function which we will use to analyze the surface with FBC is an average of height differences or of squared height differences between $h(x_0 + r, t)$ and $h(x_0, t)$, where r $(1 \leq r \leq L)$ is the distance from a boundary $x_0 = 0$ at time t. If we know the height-height correlation function between two fixed boundaries, we can get clean and clear information how the saturated surface of whole system is formed. We will measure the height-height correlation function and explain the anomalous behavior (3) through it.

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Third motivation of this paper is to suggest about a new type queuing phenomena originated from the analysis of the height-height correlation function. Queuing [12] is a common nonequilibrium phenomenon in nature. It is well established that many driven flow processes belong to the same universality class as Kardar-Parisi-Zhang (KPZ) type growth of one dimensional interfaces [7, 13]. For example, a traffic jam [14] caused by slow and fast bond of the so-called asymmetric simple exclusion process (ASEP) [15] is related to the faceting on KPZ growth. ASEP breaks translational invariance in many ways. One of them is to retain periodic boundary conditions, but to introduce a defect into the system by modifying the transition rates locally [14, 16]. By properly chosen injection/removal rates or defect strength, nonequilibrium phase transitions occur between profiles of different shapes and average densities. In our model, we map the fixed boundary condition to a defect which exists on the center of system. The defect site means that the growth at a certain site is impossible or is controlled by a probability p which is called a defect strength. That is, the fixed boundary condition $h(x_0 = 0, t) = h(x_0 = L, t) = 0$ is shifted by the mapping $x_0 \to x_0 + L/2$ to the defect site $h(x_0 = L/2, t) = 0$ with the periodic boundary condition. For $p = 0$ any deposition or evaporation process at x_0 cannot occur $(h(x_0) = 0)$, since the strength of the defect is absolutely strong and thus the surface heights cannot be freely increased by the defect. If $p \neq 0$, the deposition or evaporation process at x_0 is accepted by p and the system with $p = 1$ is the same as PBC without the defect. The height-height correlation function of our stochastic discrete model shows lateral asymmetry $C(r) \neq C(-r)$ around the defect, in contrast to KPZ-type queuing phenomena or ASEP which shows up-down symmetry breaking under the transformation $h(x) \to -h(x)$. The new queuing phenomena from the drifted EW equation (1) with a defect is physically different from usual ASEP or queuing phenomena which is related to the nonlinearity of KPZ equation [7], because it is from the linearity of the drifted EW equation (1). Therefore it is very interesting to compare our new queuing phenomena to earlier studied KPZ type queuing phenomena. In this paper, we want to investigate new queuing phenomena from the defect and the drift using our stochastic discrete model and apply it to the parking garage model [14].

II. A NOVEL METHOD TO MAKE STOCHASTIC DISCRETE MODEL

In this section, we introduce a new method to make a discrete stochastic growth model which physically corresponds to the continuum equation. Normally the surface configuration is described by the continuum Langevin equation [6]

$$\frac{\partial h(x,t)}{\partial t} = \mathcal{F}(h(x),t) + \eta(x,t) \ , \tag{4}$$

where $\mathcal{F}(h(x),t)$ depends on the surface configuration $\{h(x)\}$. In the method, the surface configurations are described in terms of integer height variables as $H \equiv \{h_i\}_{i=1}^{N} = 0, \pm 1, \pm 2, \cdots$ on a lattice. Then the continuum equation (4) can be discretized into

$$\frac{\partial h_i}{\partial t} = \mathcal{F}_i(h_i,t) + \eta_i(t) \ . \tag{5}$$

Associated with Eq. (5), the general master equation [17, 18, 19] for the surface evolution can be written as

$$\frac{\partial P(H,t)}{\partial t} = \sum_{H'} \omega(H',H) P(H',t) - \sum_{H'} \omega(H,H') P(H,t) \ . \tag{6}$$

Here $\omega(H',H)$ is the transition rate from the configuration H to the configuration H' and $P(H,t)$ is the probability that the system is in the configuration H at time t. Using the transition moments [19]

$$K_i^{(1)}(H) = \sum_{H'} (h'_i - h_i) \omega(H',H) \tag{7}$$

and

$$K_i^{(2)}(H) = \sum_{H'} (h'_i - h_i)(h'_j - h_j) \omega(H',H) \ , \tag{8}$$

the master equation (6) can be rewritten as Fokker-Planck equation [17, 18, 19]

$$\begin{aligned} \frac{\partial P(H,t)}{\partial t} &= \sum_i \frac{\partial}{\partial h_i}[K_i^{(1)}(H) P(H,t)] \\ &+ \sum_{i,j} \frac{1}{2} \frac{\partial^2}{\partial h_i \partial h_j}[K_{ij}^{(2)}(H) P(H,t)] \ , \end{aligned} \tag{9}$$

by Kramers-Moyal expansion. Therefore we can obtain the discrete version of equivalent Langevin equation from Eq. (9) as

$$\frac{\partial h_i(t)}{\partial t} = K_i^{(1)}(H) + \eta_i(t) \ , \tag{10}$$

and thus $K_i^{(1)}$ is equal to $\mathcal{F}_i$ of Eq. (5). Here the noise $\eta_i(t)$ has the properties $< \eta_i(t) >= 0$ and $< \eta_i(t) \eta_j(t') >= K_{ij}^{(2)} \delta(t - t')$. When the noise is white, $K_{ij}^{(2)}$ is equal to $2D\delta_{ij}$.

Normally the evolution process in a stochastic surface growth model is defined by one-particle deposition or evaporation in a unit evolution process [6]. Hence if only one-particle deposition($h_i \rightarrow h_i + a$) or evaporation($h_i \rightarrow h_i - a$) is imposed at a randomly chosen site i in a unit evolution process, then $K_i^{(1)}$ and $K_{ij}^{(2)}$ are

$$\begin{aligned} K_i^{(1)}(H) &= a\omega_{id} - a\omega_{ie} \\ K_{ij}^{(2)}(H) &= \begin{cases} 0 & , i \neq j \\ a^2\omega_{id} + a^2\omega_{ie} & , i = j \end{cases} \end{aligned} \qquad (11)$$

from Eqs. (7) and (8), where ω_{id} is $\omega(\{h_1, h_2, \cdots, h_i, \cdots, h_N\}, \{h_1, h_2, \cdots, h_i + a, \cdots, h_N\})$ and ω_{ie} is $\omega(\{h_1, h_2, \cdots, h_i, \cdots, h_N\}, \{h_1, h_2, \cdots, h_i - a, \cdots, h_N\})$.Then from the Eq. (11), these rates are

$$\omega_{id} = \left(\frac{K_i^{(1)}}{2a} + \frac{D}{a^2} \right) \cdot \Theta \left(\frac{K_i^{(1)}}{2a} + \frac{D}{a^2} \right) , \qquad (12)$$

$$\omega_{ie} = \left(-\frac{K_i^{(1)}}{2a} + \frac{D}{a^2} \right) \cdot \Theta \left(-\frac{K_i^{(1)}}{2a} + \frac{D}{a^2} \right) . \qquad (13)$$

Here we impose the unit step function $\Theta(x)$, i.e. $\Theta(x) = 1$ for $x > 0$ and $\Theta(x) = 0$ for $x \leq 0$, to the transition rates ω_{id} and ω_{ie}, because the transition rates must be always positive. If $\eta_i(t)$ is the local white noise, the evolution site i is randomly chosen to apply the rates (12) and (13).

Now we want to describe the discrete stochastic model which exactly correspond to Eq. (4) on an one-dimensional ($1d$) substrate in detail. Generalization to that on higher-dimensional substrates can easily be obtained from the description of the $1d$ model. The discrete model is defined by the following steps. (i) Select a site i randomly. (ii) Calculate the deposition rate (the rate for $h_i \rightarrow h_i + 1$) ω_{id} and the evaporation rate (the rate for $h_i \rightarrow h_i - 1$) ω_{ie} from Eqs. (12) and (13). (We set $a = 1$.) (iii) Compare a random number R ($0 < R < 1$) with the deposition probability $P_{id} = \omega_{id}/(\omega_{id} + \omega_{ie})$ and the evaporation probability $P_{ie} = \omega_{ie}/(\omega_{id} + \omega_{ie})$. If $R \leq P_{id}$, take the deposition process. Otherwise take the evaporation process.

III. DYNAMICAL SCALING PROPERTIES OF THE STOCHASTIC MODEL

We now report the numerical results of our stochastic discrete model for the drifted EW equation with the defect which is controlled by a strength p. The initial surface is always set to be flat ($h_i(t = 0) = 0$) and the lateral periodic condition is always imposed. All data are taken by average over more than 500 independent runs. We first explain the scaling properties of the surface width for several defect strengths p. The first transition moment ${K_i}^{(1)}$ of drifted EW equation (1) at a randomly selected site i is

$$\begin{aligned} {K_i}^{(1)} &= [\nu_2 \nabla^2 h - v \nabla h]_i \\ &= \nu_2 [h_{i+1} + h_{i-1} - 2h_i] - \frac{v}{2}[h_{i+1} - h_{i-1}]. \end{aligned} \qquad (14)$$

We use the parameters $\nu_2 = 1$, $v = 1$ and $D = 0.01$ for Eq. (1). We check the dynamical scaling behaviors for other parameter values to obtain the same behaviors for $\nu_2 = 1$, $v = 1$ and $D = 0.01$. Used system sizes are $L = (2^6 + 1), \cdots, (2^{12} + 1)$ and the defect is located at the center site $x_0 = (L - 1)/2 + 1$ of all systems.

Usually the surface roughness is defined as $W(L, t) = \sqrt{\langle \overline{h^2} \rangle - \langle \overline{h}^2 \rangle}$. The scaling relation of W satisfies the following behavior [6]

$$\begin{aligned} W(L, t) &\sim L^{\alpha} f(t/L^z) \\ &= \begin{cases} t^{\beta} , & t \ll L^z \\ L^{\alpha} , & t \gg L^z . \end{cases} \end{aligned} \qquad (15)$$

Figure 1(a) shows the obtained saturated surface width $W_{sat}(= W(t \gg L^z))$ from the stochastic model for various system size L and defect strength p. W_{sat} satisfies the scaling relation $W_{sat} \sim L^{\alpha}$ with $\alpha = 0.50(1)$ for $p = 0.1$ and $p = 1$. Since $p = 1$ case is the same as that without the defect, α should be EW value $\alpha = 1/2$. Even though the defect strength is sufficiently large ($p = 0.1$), the surface roughness still follows normal EW behavior. In contrast, for perfect defect or $p = 0$, the surface width W follows the anomalous behavior with $\alpha = 0.25(1)$ instead of EW behavior. The main plot of Fig. 1(b) shows that $W(L, t)$ for various L and t collapses well to scaling function Eq. (15) for $p = 0.1$. We use the exponents $\alpha = 0.50$ from the fitting of $W \sim L^{\alpha}(t \gg L^z)$ in Fig. 1(a) and $\beta = 0.25$ ($W \sim t^{\beta}(t \ll L^z)$) as shown in the inset of Fig. 1(a). Therefore the dynamic exponent is $z = \alpha/\beta = 2$ which is the value of the normal EW universality class. The results in Fig. 1(b) show that the dynamical scaling property for $p \neq 0$ satisfies the normal EW behavior. In contrast, the exponents are changed for $p = 0$ (Fig. 1(c)). The time dependence of $W(L, t)$ of the model at $p = 0$ is shown in the inset of Fig. 1(c). $\beta = 0.249(1)$ in Fig. 1(c) is obtained by applying the relation $W \sim t^{\beta}(t \ll L^z)$ to $W(t)$ of the system with $L = 2^{12} + 1$. We also check the dynamical scaling relation of Eq. (15) by plotting $\ln(W/L^{\alpha})$ against $\ln(t/L^z)$ in Fig. 1(c). The data collapse well to the scaling function Eq. (15) with $\alpha = 0.25$ and $z = 1$. The results in Fig. 1 clearly show that the anomalous behavior occurs only when the perfect defect ($p = 0$) exists in the system. These results agree with the analytic result of Ref. [1]. From these results, we confirm that a sudden crossover from the anomalous behavior to the normal EW behavior occurs as soon as p deviates from $p = 0$.

To understand the physical origin of the anomalous interface profile which is induced from the defect (FBC) and the drift term in Eq. (1), we study several height-height correlation functions. The height-height correlation function which has been extensively used for the analysis of surface roughness [6] should be one of the efficient methods to see the physical mechanism. Normally

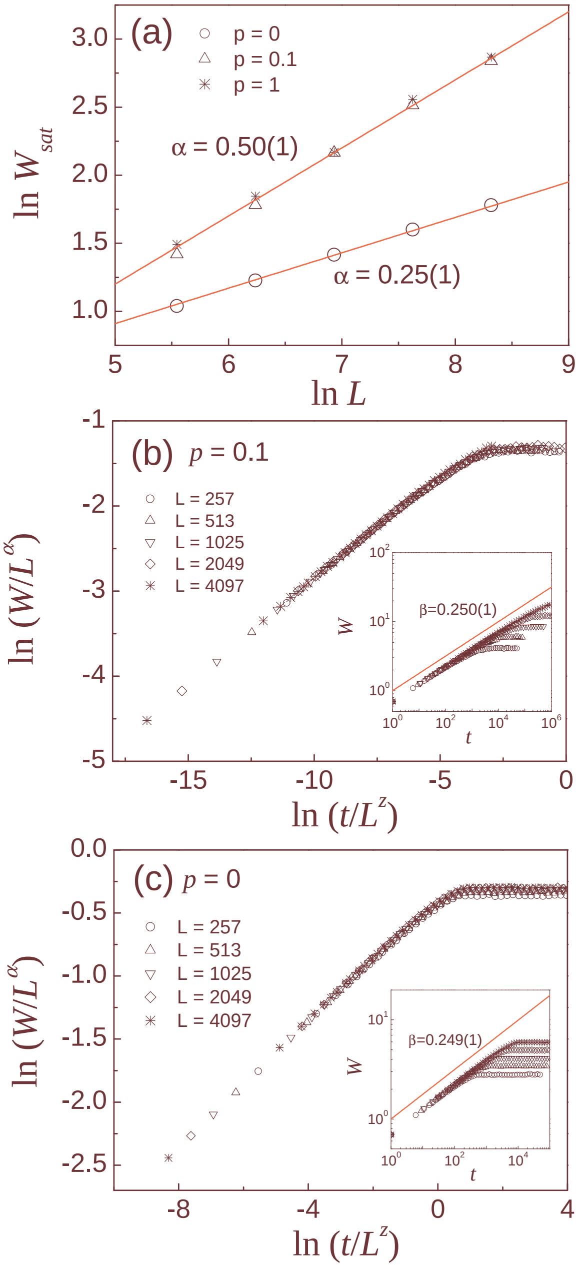

FIG. 1: (Color online) (a) Plot of $\ln W_{sat}$ against $\ln L$ in the saturation regime ($t \gg L^z$). The straight lines represent the relation $W_{sat} \sim L^{\alpha}$. $\alpha = 0.25(1), 0.5(1), 0.5(1)$ for $p = 0$, $p = 0.1$, and $p = 1$, respectively. Used system sizes are $L = (2^6+1), \cdots, (2^{12}+1)$ and used parameters are $\nu = 1, v = 1, D = 0.01$. (b) The plot of $\ln(W/L^{\alpha})$ for the different L against $\ln(t/L^z)$ with $\alpha = 1/2$ and $z = 2$ at $p = 0.1$. The numerical data for W nicely collapse to one curve which satisfies the relation (15). (c) Scaling plot showing that the data for $\ln(W/L^{\alpha})$ plotted against $\ln(t/L^z)$ for various L collapse to a single curve supporting the scaling function (15) with $\alpha = 1/4$ and $z = 1$ at $p = 0$. Insets of (b) and (c) are log-log plots of W against t.

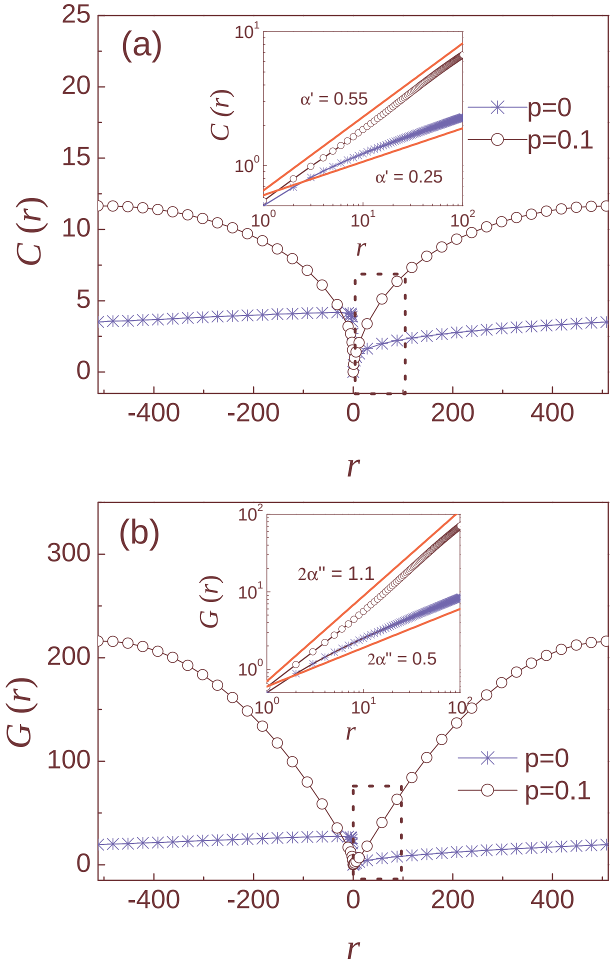

FIG. 2: (Color online) (a) Plots of the height-height correlation function (17) for $p = 0$ and $p = 0.1$ when $t \gg L^z$. Inset shows the log-log plot of the dotted square part in the main plot. $C(r)$ satisfies the relation $C \sim r^{\alpha'}$ with $\alpha' = 0.55(1)$ ($p = 0.1$) and $\alpha' = 0.25(1)$ ($p = 0$). (b) Plots of the height-height correlation function Eq. (18) for $p = 0$ and $p = 0.1$. Inset shows the log-log plot of the dotted square part in the main plot. $G(r)$ satisfies the relation $G \sim r^{2\alpha''}$ with $2\alpha'' = 1.10(1)$ ($p = 0.1$) and $2\alpha'' = 0.50(1)$ ($p = 0$). Used system size is $L = 1025$.

the height-height correlation function [6] means

$$G_{PBC}(r,t) = \frac{1}{L}\sum_{x=1}^{L}\left\langle [h(x,t) - h(x+r,t)]^2 \right\rangle \ , \qquad (16)$$

when the periodic boundary condition is imposed. However when a local defect is the relevant factor for the dynamical scaling properties of the interface, the correlation function which measures the height differences between $h(x_0)$ and $h(x,t)(x \neq x_0)$ should be more powerful one. One of such correlation functions is the naive and simple height-height correlation function $\widetilde{C}(r,t) = \langle h(x_0+r,t) - h(x_0,t)\rangle$. Here $\langle\ \rangle$ means the average over independent runs and r means the position from the defect $x_0(= L/2)$. However, $\widetilde{C}(r,t)$ cannot characterize the surface configuration physically well for the equilibrium surfaces in which the deposition and evaporation processes occur with nearly the same probability. The equilibrium surface fluctuates around $\langle h\rangle = 0$ and $\widetilde{C}(r,t)$ has no information for the surface height correlation around the defect. Instead, we use two height-height correlation functions $C(r,t)$ and $G(r,t)$ defined as

$$C(r,t) \equiv \langle |h(x_0 + r, t) - h(x_0, t)|\rangle \tag{17}$$

and

$$G(r,t) \equiv \left\langle |h(x_0 + r, t) - h(x_0, t)|^2 \right\rangle \ , \tag{18}$$

respectively. For the analysis of the saturated surface configurations, we concentrate only on the saturated correlation functions $C(r, t \gg L^z)(\equiv C(r))$ and $G(r, t \gg L^z)(\equiv G(r))$. Used system size for the measurement of $C(r)$ and $G(r)$ is $L = 1025$ and thus the defect site is located at $x_0 = 513$. These two height-height correlation functions are expected to scale as $C(r) \sim r^{\alpha'}$ and $G(r) \sim r^{2\alpha''}$ as shown in Figs. 2(a) and (b). Furthermore for $p = 0$ we obtain the exponents $\alpha' = \alpha'' = 0.25(1)$, which is very close to the roughness exponent $\alpha = 0.25(1)$ in Fig. 1(a). For $p = 0$,

$$C(r) = \langle |h(x_0 + r, t)|\rangle \tag{19}$$

and

$$G(r) = \left\langle |h(x_0 + r, t)|^2\right\rangle \tag{20}$$

and thus we clearly see the $\langle |h(x_0 + r, t)|\rangle \simeq r^{1/4}$, which decide the anomalous behavior $\alpha = 1/4$. This means the saturated surface configurations for the drifted EW equation with a defect satisfies

$$\begin{aligned} W &\sim \langle |h(x_0 + r, t)|\rangle \\ &\sim \sqrt{\langle h^2(x_0 + r, t)\rangle} \ . \end{aligned} \tag{21}$$

Therefore physically the surface configuration is decided by the FBC (or the defect), which does not allow the surface fluctuation freely. However, PBC allows the surface fluctuation freely even though there exists the drift term $\partial_x h$.

In contrast, as soon as the growth at the defect is allowed even with a very low probability, we get $\alpha' = \alpha'' \approx 0.5$, which is almost the same as roughness exponent $\alpha = 0.5$ of EW universality class. (See the data for $p = 0.1$ in Fig. 2.) Therefore the anomalous behavior $\alpha = \alpha' = \alpha'' = 1/4$ for $p = 0$ disappears and are changed into $\alpha = \alpha' = \alpha'' = 1/2$ as soon as the defect condition is released or for $p \neq 0$.

Even though the defect exists, the drift term does not change the universality of the dynamical surface scaling for $0 < p < 1$. Therefore the height-height correlation function has a lateral symmetry $C(r) = C(-r)$ or $G(r) = G(-r)$ for $p \neq 0$ as for the normal EW equation (2). For $p = 0$, the noise-generated surface structure from the defect is pushed by the drift and transmitted all over the system. Then the flow of the surface structure comes back through the boundary suddenly disappears at the defect. Therefore the height-height correlation function shows the asymmetry $C(r) \neq C(-r)$ and $G(r) \neq G(-r)$. This asymmetric behavior of $C(r)$ and $G(r)$ is a unique behavior for the drifted EW equation with a perfect defect. In contrast the height-height correlation function around a defect for KPZ-type surface growth [14] always shows the lateral symmetry $\widetilde{C}(r) = \widetilde{C}(-r)$. In KPZ-type surface growth model with the defect [14], the height-height correlation function $\widetilde{C}(r,p)$ changes from $\widetilde{C}(r,p) \sim A|r| + B|r|^{\alpha'}$ for $p < p_c$ to $\widetilde{C}(r,p) \sim B|r|^{\alpha'}$

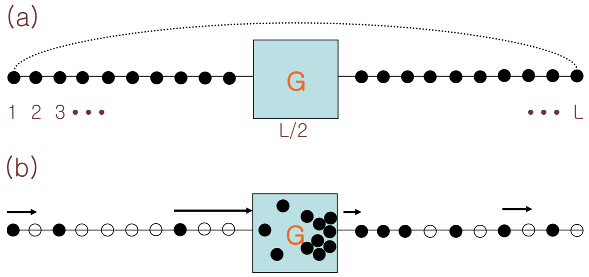

FIG. 3: (Color online) Schematic representation of the queuing phenomena which emerges in the stochastic growth model with a defect. Periodic boundary condition is used. (a) The initial distribution of cars. (b) A steady state configuration. Arrows denote the local velocities of cars. Cars move out from garage with a very low speed and they are packed at the exit, because of the defect. In the middle of the road, cars maintain their average velocity. On the contrary, the speed with which cars get in the garage is much faster than the average velocity.

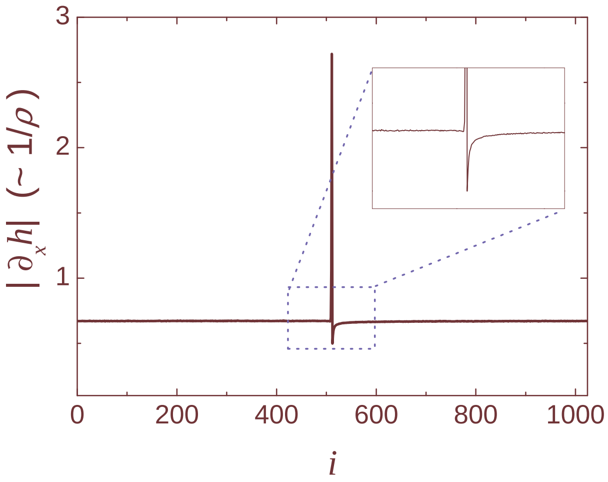

FIG. 4: (Color online) Plot of $|\partial_x h|$ against the position i. Used system size is $L = 1025$.

for $p \geq p_c$. It means that the queueing effect of the defect spreads out entire system ($p \geq p_c$) or affects only around region of the defect ($p < p_c$). The phase transition argument of KPZ-type surface growth is analogous to the queuing effect by a defect which is located at a certain point of lane [14]. On the other hand, the height-height correlation functions which we measured always maintains the simple power behavior $C(r) \sim r^{\alpha'}$ and $G(r) \sim r^{\alpha''}$. Instead, it shows the sudden crossover of the exponents α' and α'' as soon as the defect is weakly imposed (or $p \neq 0$). That is, the effect of the defect and the drift influences only when the defect strength is absolutely strong (or $p = 0$).

IV. APPLICATION TO QUEUING PHENOMENA

The asymmetric form of the interface profile by the defect and drift can be applied to a kind of the queuing phenomena or car condensation in a parking garage model [14, 16]. Let's think of the traffic flow of cars on an one-dimensional road with a periodic boundary condition (or a ring-type road). The defect site in our model is then reinterpreted as the parking garage (See Fig. 3). Initially all cars on the road are equally distributed everywhere on the road as shown in Fig. 3(a). If the drift EW equation (1) with a defect (garage) describes a queuing phenomena, the absolute gradient of the height $|\partial_x h(t)|_i = |h_i(t) - h_{i-1}(t)|$ at i-th site can be mapped to the effective speed v_i of a car around the site i at the given moment t due to the drift term $v|\partial_x h|$. In the steady state the car density ρ_i at the site i is then inversely proportional to $|\partial_x h|_i = |h_i - h_{i-1}|$ as $v_i \propto |\partial_x h|_i \propto 1/\rho$.

Figure 4 shows $|\partial_x h|_i$ for $p = 0$ in the saturated state (or steady state) when $t \gg L^z$. $|\partial_x h|_i$ increases very rapidly as i increases from the defect position and immediately reaches a certain average value. Average value remains until i approaches the defect site from the left, and $|\partial_x h|_i$ grows very rapidly to the highest value in the limit $i \to x_o-$. These results correspond to the following steady-state traffic flow. The cars slowly move out from the parking garage by a sort obstruction at the exit or by a lazy parking charge collector. Thus they are packed near the exit of the garage and the density ρ of cars at the exit is very high. As soon as cars enter the road, the speed and car density reach to the average value $|\partial_x h|_i = v_a \sim 1/\rho_a \simeq const.$ and maintain the average values in the middle of road. When cars come close to the entrance of the garage, the speed of cars gets much faster. Therefore the density of cars at the entrance becomes very low.

V. SUMMARY

In this paper, we presented a simple stochastic discrete model which describes the drifted EW equation (1) with a defect. From the simple model, we can easily show the anomalous behavior of the surface fluctuation by the drift and defect. The scaling exponents show the anomalous behavior $\alpha = 1/4$, $\beta = 1/4$, and $z = 1$, only when the defect strength is $p = 0$. The exponents are suddenly changed to normal EW exponents as soon as the defect strength is weakly imposed ($p \neq 0$). We also measure the height-height correlation functions to characterize the asymmetric interface profile and to explain the exact physical role of the drift term and defect. The height-height correlation functions show that the drift and the perfect defect ($p = 0$) makes the asymmetry $C(r) \neq C(-r)$ or $G(r) \neq G(-r)$. These height-height correlation functions satisfy the power law $C(r) \sim r^{\alpha'}$ and $G(r) \sim r^{2\alpha''}$ with $\alpha' = \alpha'' = 1/4$. The height-height correlation function exponents and the roughness exponent have the same value $\alpha = \alpha' = \alpha'' = 1/4$. Therefore the saturated surface configuration for drifted EW equation with the defect is solely decided by the defect. The asymmetry of the height-height correlation functions is very unique when compared to the correlation functions for KPZ-type growth model with the defect which always shows the symmetry $\widetilde{C}(r) = \widetilde{C}(-r)$. From this asymmetry we suggest a new queuing process around the defect.

This work is supported by Korea Research Foundation Grant No. KRF-2004-015-C00185.

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